



# **MOBILE CPU POWER SUPPLY CONTROLLER**

# **FEATURES**

- **Power Stage Input Voltage Range of 3 V to 28 V**
- **Single-Chip Dynamic Output Voltage Transition Solution**
- **Hysteretic Controller Provides Fast Transient Response Time and Reduced Output Capacitance**
- **Two Linear Regulator Controllers Regulating Clock and I/O Voltages**
- **Internal 2-A (Typ) Gate Drivers With Bootstrap Diode For Increased Efficiency**
- **5-Bit Dynamic VID**
- **Active Droop Compensation Enables Tight Dynamic Regulation for Reduced Output Capacitance**
- **VGATE Terminal Provides Power-Good Signal for All Three Outputs**
- **Enable External Terminal (ENABLE\_EXT)**
- **32-Pin TSSOP PowerPAD<sup>™</sup> Enhances Thermal Performance**
- **1% Reference Voltage Accuracy**

# **APPLICATIONS**

- **Intel Mobile CPUs With SpeedStep Technology**
- **AMD Mobile CPUs With PowerNow! Technology**
- **DSP Processors**
- **Other One, Two, or Three Output Point-of-Load Applications**

# **DESCRIPTION**

The TPS5300 is a hysteretic synchronous-buck controller, with two on-chip linear regulator controllers, incorporating dynamic output voltage positioning



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programmable supply voltage to a mobile processor or other processor power applications. A ripple regulator provides the core voltage, while two linear regulator drivers regulate external NPN power transistors for the I/O and CLK voltages. A 5-bit voltage identification (VID) DAC allows programming for the ripple regulator voltage to values between 0.925 V to 1.275 V in 25-mV steps and 1.3 V to 2 V in 50-mV steps. Other voltage ranges and steps can be easily set. The fast transient response time and active voltage DROOP positioning reduce the number of output capacitors required to keep the output voltage within tight dynamic voltage regulation limits. The power saving mode (PSM) allows the user to select a single operating ramp or allows the controller to automatically switch to lower frequencies at low loads. The high-gain current sense differential amplifier allows the use of small-value sense resistors that minimize conduction losses.

technology. The TPS5300 provides a precise,



#### **Output Voltage Transient Load Response**

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#### **description (continued)**

The TPS5300 includes high-side and low-side gate drivers rated at 2 A typical, that enable efficient operation at higher frequencies and drive larger or multiple power MOSFETs (such as 50-A output current applications). An adaptive dead-time circuit minimizes dead-time losses while preventing cross-conduction of high-side and low-side switches. All three outputs power up together as they track the same user programmable slowstart voltage. The enable external (ENABLE\_EXT) terminal allows the TPS5300 to activate external switching controllers for additional system power requirements.

The TPS5300 features  $V_{CC}$  undervoltage lockout, output overvoltage protection, output undervoltage protection, and user-programmable overcurrent protection, and is packaged in a small 32-pin TSSOP PowerPAD package.

#### **pin assignments**





#### **absolute maximum ratings over operating free-air temperature (unless otherwise noted)†**



† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**



#### **JUNCTION-CASE THERMAL RESISTANCE TABLE**



‡ Test Board Conditions:

- 1. Thickness: 0.062"
- 2.  $3" \times 3"$  (for packages < 27 mm long)
- 3.  $4" \times 4"$  (for packages > 27 mm long)
- 4. 2 oz. Copper traces located on the top of the board (0,071 mm thick )
- 5. Copper areas located on the top and bottom of the PCB for soldering
- 6. Power and ground planes, 1 oz. Copper (0,036 mm thick)
- 7. Thermal vias, 0,33 mm diameter, 1,5 mm pitch
- 8. Thermal isolation of power plane

For more information, refer to TI technical brief SLMA002.



**TPS5300**

 $SLV$ S334A - DECEMBER 2000 - REVISED SEPTEMBER 2001 SLVS334A – DECEMBER 2000 – REVISED SEPTEMBER 2001

# functional schematic **functional schematic**



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# **recommended operating conditions, 0 < TJ < 125**°**C (unless otherwise noted)**



### **dc and ac electrical characteristics over recommended operating free-air temperature range, 0 < TJ < 125**°**C, VIN = 3 V – 28 V (unless otherwise noted)**



NOTES: 1. Cumulative reference accuracy is the combined accuracy of the reference voltage and the input offset voltage of the hysteretic comparator. Cumulative accuracy equals to the average of the low-level and high-level thresholds of the hysteretic comparator.

2. Ensured by design, not production tested.



# **electrical characteristics over recommended operating free-air temperature range, 0 < TJ < 125**°**C, VIN = 3 V – 28 V (unless otherwise noted) (continued)**



NOTES: 2. Ensured by design, not production tested.

3. The VBIAS voltage is required to be a quiet bias supply for the TPS5300 control logic. External noisy loads should use VCC instead of the VBIAS voltage.



# **electrical characteristics over recommended operating free-air temperature range, 0 < TJ < 125**°**C, VIN = 3 V – 28 V (see test circuits) (unless otherwise noted) (continued)**



NOTES: 2. Ensured by design, not production tested.

4. The pulldown (sink) circuit of the high-side driver is a MOSFET transistor referenced to DRVGND. The driver circuits are bipolar and MOSFET transistors in parallel. The peak output current rating is the combined current rating from the bipolar and MOSFET transistors. The output resistance is the  $r_{ds(on)}$  of the MOSFET transistor when the voltage on the driver output is less than the saturation voltage of the bipolar transistor.

5. Rise and fall times are measured from 10% to 90% of pulsed values.



# **electrical characteristics over recommended operating free-air temperature range, 0 < TJ < 125**°**C, VIN = 3 V – 28 V (see test circuits) (unless otherwise noted) (continued)**



NOTES: 2. Ensured by design, not production tested.

4. The pulldown (sink) circuit of the high-side driver is a MOSFET transistor referenced to DRVGND. The driver circuits are bipolar and MOSFET transistors in parallel. The peak output current rating is the combined current rating from the bipolar and MOSFET transistors. The output resistance is the  $r_{ds(on)}$  of the MOSFET transistor when the voltage on the driver output is less than the saturation voltage of the bipolar transistor.

# **Terminal Functions**







# **Terminal Functions (Continued)**

# **detailed description**

#### **reference/voltage identification**

The reference /voltage programming (VP) section consists of a temperature-compensated, bandgap reference and a 5-bit voltage selection network. The five VID pins are inputs to the VID selection network and are TTL compatible inputs that are internally pulled up to  $V_{CC}$  with pullup resistors. The internal reference voltage can be programmed from 0.925 V to 2 V with the VID pins. The VID codes are listed in Table 1. The output voltage of the VP network, V<sub>ref</sub>, is within  $\pm 1.5\%$  of the nominal setting. The  $\pm 1.5\%$  tolerance is over the full VP range of 0.925 V to 2 V, and includes a junction temperature range of 0°C to 125°C, and a V<sub>CC</sub> range of 4.5 V to 5.5 V. The output of the reference/VP network is indirectly brought out through a buffer to the VREFB pin. The voltage on this pin will be within  $\pm 5$  mV of V<sub>ref</sub>. It is not recommended to drive loads with VREFB, other than setting the hysteresis of the hysteretic comparator, because the current drawn from VREFB sets the charging current for the slowstart capacitor. Refer to the slowstart section for additional information.



# **detailed description (continued)**



# **Table 1. Voltage Programming Code**

NOTE: If the VID bits are set to 11111 or 01111, then the high-side and low-side driver outputs will be set low.



#### **detailed description (continued)**

#### **dynamic VID change**

Dynamic VID change controls the rate of change of the programmed VID to allow transitioning within 100 µs, while controlling the dv/dt to avoid large input surge currents. VID could change with any input voltage, output voltage, or output current. A new change is ignored until the current transition is finished. Program the transition by adding a capacitor from DT\_SET to ANAGND.

$$
C_{\text{DT\_SET}} = \frac{I_{\Delta t} \times \Delta t}{\Delta V_{\text{REF}}} = \frac{14 \,\mu\text{A} \times \Delta t}{V_{\text{REF2}} - V_{\text{REF1}}}
$$

#### **hysteretic comparator**

The hysteretic comparator regulates the output voltage of the synchronous-buck converter. The hysteresis is set by two external resistors and is centered around VREFB. The two external resistors form a resistor divider from VREFB to ANAGND, and the divided down voltage connects to the VHYST terminal. The hysteresis of the comparator will be equal to twice the voltage that is across the VREFB and VHYST pins. The maximum hysteresis setting is 60 mV.

#### **ramp generator**

The ramp generator circuit is partially composed of the PSM circuit. An external resistor from PH to VSENSE\_CORE superimposes a ramp (proportional to  $V_1$  and  $V_O$ ) onto the feedback voltage. This allows increasing the operating frequency, and reduces frequency dependance on the output filter values. A capacitor can be used to provide ac-coupling. Also, connecting a resistor from V<sub>I</sub> to VSENSE\_CORE allows feed forward to counteract any dc offsets due to the ramp generator or propagation delays limiting duty cycle.

#### **power saving mode/latch**

The power saving mode circuit reduces the operating frequency of the ripple regulator during light load. This helps boost the efficiency during light loads by reducing the switching losses. Care should be taken to not allow rms current losses to exceed the switching losses. A 2-bit binary weighted resistor ramp circuit allows setting four operating frequencies.

The PSM/LATCH terminal allows disabling of the fault latch (see Table 2). This allows the user to troubleshoot or implement an external protection circuit.

	<b>Pin Voltage</b>	<b>Function</b>
	$<$ (ANAGND – 0.3 V)	Disable PSM and disable fault latch
	ANAGND to 1.8 V	Disable PSM and enable fault latch
	2.3 V to VBIAS	Enable PSM and enable fault latch
4	$>$ (VBIAS + 0.3 V)	Enable PSM and disable fault latch

**Table 2. PSM Program Modes**

#### **active voltage DROOP positioning**

The droop compensation network reduces the load transient overshoot/undershoot on  $V_{O}$ , relative to  $V_{ref}$ . V<sub>O(max)</sub> is programmed to a voltage greater than V<sub>ref</sub> in the Application Information drawing by an external resistor divider from  $V_{\Omega}$  to the VSENSE\_CORE pin to reduce the undershoot on  $V_{\Omega UT}$  during a low to high load transient. The overshoot during a high-to-low load transient is reduced by subtracting the voltage that is on the DROOP pin from V<sub>ref</sub>. The voltage on the IOUT pin is divided down with an external resistor divider, and connected to the DROOP pin. Thus, under loaded conditions,  $V_O$  is regulated to  $V_{O(max)} - V_{(DROOP)}$ . The continuous sensing of the inductor current allows a fast regulating voltage adjustment allowing higher transient repetition rates.



### **detailed description (continued)**

#### **low-side driver**

The low-side driver is designed to drive low r<sub>ds(on)</sub>, N-channel MOSFETs. The current of the driver is typically 2-A source and 3.3-A sink. The supply to the low-side driver is internally connected to  $V_{\text{CC}}$ .

#### **high-side driver**

The high-side driver is designed to drive low r<sub>ds(on)</sub> N-channel MOSFETs. The current of the driver is typically 2-A source and 3.3-A sink. The high-side driver is configured as a floating bootstrap driver. The internal bootstrap diode, connected between the DRV and BOOT pins, is a Schottky diode for improved drive efficiency. The maximum voltage that can be applied between the BOOT pin and ground is 35 V.

#### **deadtime control**

The deadtime control prevents shoot-through current from flowing through the main power FET's during the switching transitions by actively controlling the turnon times of the MOSFET drivers. The high-side driver is not allowed to turn on until the gate drive voltage to the low-side FET is below 1.7 V. The low-side driver is not allowed to turn on until the gate drive voltage from the high-side FET to PH is below 1.3 V.

#### **current sensing**

Current sensing is achieved by sensing the voltage across a current-sense resistor placed in series between the output inductor and the output capacitors. The sensing network consists of a high bandwidth differential amplifier with a gain of 25x to allow using sense resistors with values as low as 1 mΩ. Sensing occurs at all times to allow having *real-time* information for quick response during an active voltage droop positioning transition. The voltage on the IOUT pin equals 25 times the sensed voltage.

#### **VR\_ON**

The VR\_ON terminal is a TTL compatible digital pin that is used to enable the controller. When VR\_ON is low, the output drivers are low, the linear regulator drivers are off, and the slowstart capacitor is discharged. When VR\_ON goes high, the short across the slowstart capacitor is released and normal converter operation begins. When the system logic supply is connected to the VR\_ON pin, the VR\_ON pin can control power sequencing by locking out controller operation until the system logic supply exceeds the input threshold voltage of the VR\_ON circuit. Thus, V<sub>CC</sub> and the system logic supply (either 5 V or 3.3 V) must be above UVLO thresholds before the controller is allowed to start up. Likewise, a microprocessor or other external logic can also control the sequencing through VR\_ON.

#### **VBIAS undervoltage lockout**

The VBIAS undervoltage-lockout circuit disables the controller, while VBIAS is below the 4.46-V start threshold during power up. The controller is disabled when VBIAS goes below 3.3 V. While the controller is disabled, the output drivers will be low and the slowstart capacitor will be shorted. When VBIAS exceeds the start threshold, the short across the slowstart capacitor is released and normal converter operation begins.

#### **IO linear regulator driver**

The IO linear regulator driver circuit drives a high power NPN external power transistor, allowing external power dissipation. The IO voltage is ramped up with the slowstart with the other two converters. Under voltage protection protects against hard shorts or extreme loading. The VSENSE\_IO voltage is monitored by the VGATE (powergood) circuit. A fault or shutdown on any converter will shut down the linear regulator.

#### **CLK linear regulator driver**

The CLK linear regulator driver circuit drives a lower power NPN external power transistor, allowing external power dissipation. The CLK voltage is ramped up with the slowstart with the other two converters. Under voltage protection protects against hard shorts or extreme loading. The VSENSE\_CLK voltage is monitored by the VGATE (powergood) circuit. A fault or shutdown on any converter will shut down the linear regulator.



### **detailed description (continued)**

#### **slowstart**

The slowstart circuit controls the rate at which  $V_{\text{OUT}}$  powers up. A capacitor is connected between the SLOWST and ANAGND pins and is charged by an internal current source. The value of the current source is proportional to the reference voltage, so that the charging rate of C(SLOWST) is proportional to the reference voltage. By making the charging current proportional to V<sub>ref</sub>, the power up time for V<sub>O</sub> will be independent of V<sub>ref</sub>. Thus,  $C_{\rm(SLOWST)}$  can remain the same value for all VP settings. The slowstart charging current is determined by the following equation:

 $I_{\text{SLOWSTART}} = \frac{I(VREFB)}{5}$  $\frac{12.6}{5}$  (amps)

where,  $I_{(VREFB)}$  is the current flowing out of the VREFB terminal. It is recommended that no additional loads be connected to VREFB, other than the resistor divider for setting the hysteresis voltage. Thus, these resistor values will determine the slowstart charging current. The maximum current that can be sourced by the VREFB circuit is 500 µA. The equation for setting the slowstart time is:

 $t_{\text{SLOWSTART}} = 5 \times C_{\text{(SLOWSTART)}} \times R_{\text{(VREFB)}}$  (seconds)

where,  $R_{\text{(VRFFB)}}$  is the total external resistance from VREFB to ANAGND.

#### **VGATE**

The VGATE circuit monitors for an undervoltage condition on V<sub>O(VSENSE\_CORE)</sub>, V<sub>O(VSENSE\_IO)</sub>, and V<sub>O(VSENSE\_CLK)</sub>. If any V<sub>O</sub> is 7% below its reference voltage, or if any UVLO (V<sub>cc</sub>, VR\_ON) threshold is not reached, then the VGATE pin is pulled low. The VGATE terminal is an open drain output.

#### **overvoltage protection**

The overvoltage protection circuit monitors  $\rm V_{O(VSENSE\_CORE)},$   $\rm V_{O(VSENSE\_IO)}$ , and  $\rm V_{O(VSENSE\_CLK)}$  for an overvoltage condition. If any V<sub>O</sub> is 15% above its reference voltage, then a fault latch is set, then both the ripple regulator output drivers and the linear regulator drivers are turned off. The latch will remain set until VBIAS goes below the undervoltage lockout value or until VR\_ON is pulled low.

#### **overcurrent protection**

The overcurrent protection circuit monitors the current through the current sense resistor. The overcurrent threshold is adjustable with an external resistor divider between IOUT and ANAGND terminals, with the divider voltage connected to the OCP terminal. If the voltage on the OCP terminal exceeds 200 mV, then a fault latch is set and the output drivers (ripple regulator and linear regulators) are turned off. The latch remains set until VBIAS goes below the undervoltage lockout value or until VR\_ON is pulled low.

#### **thermal shutdown**

Thermal shutdown disables the controller if the junction temperature exceeds the 165°C thermal shutdown trip point. The hysteresis is 10°C.



# **APPLICATION INFORMATION**

Figure 1 is a standard application schematic. The circuit can be divided into the power-stage section and the control-circuit section. The power stage that includes the power FETs (Q1–Q3), input capacitor (C2), output filter (L1 and C3), and the current sense resistor (R1) must be tailored to the input/output requirements of the application. The design documentation and test results for different mobile CPU power supplies covering core current from 13 A and up to 40 A is available from the factory upon request or can be found in applications notes. The control circuit is basically the same for all applications with minor tweaking of specific values.

The main waveforms are shown in Figure 2 through Figure 5. These waveforms include the following:

- The output ripple and Vds voltage of the low-side FET in the whole input voltage range (see Figure 2).
- The dynamic output voltage change between the performance and battery modes of operation (see Figure 3).
- The transient response characteristics on the load current step up and down transitions (see Figure 4).
- The typical start-up waveforms for core, clock and I/O voltages (see Figure 5).

The waveforms confirm the excellent dynamic characteristics of the hysteretic controller. The modification, that includes an additional ramp signal superimposed to the input VSENSE\_CORE internally and externally by circuits R17, R22, C13, and C10 makes the switching frequency independent of the output filter characteristics. It also decreases the comparator delay times by increasing efficiency overdrive. This approach is shown in Figure 6.





NOTES: A. Contact factory or see application notes for documentation and test results of different mobile core regulator applications at the output current up to 40 A.

B. R21 allows VID code voltage adjustment.







#### **APPLICATION INFORMATION**







**Figure 3. Dynamic VID-Code Change Waveforms From 1.35 V to 1.6 V and Back**





#### **APPLICATION INFORMATION**





#### **APPLICATION INFORMATION**

#### **switching cycle and frequency calculation**

The switching cycle calculation is shown below.

$$
T_S = \frac{V_I \times \text{Cadd} \times \text{Hyst} \times \text{Rad}}{V_O \times (V_I - V_O)} + \text{Tdel1} \times \frac{V_I}{V_O} + \text{Tdel2} \times \frac{V_I}{V_I - V_O}
$$

where, V<sub>I</sub> = input voltage, V<sub>O</sub> = output voltage, Cadd = C10 and Radd = R22 + R17 in Figure 1, Hyst is the hysteresis window, Tdel1 and Tdel2 are the comparator and drive circuit delays when the high-side and low-side FETs turn on correspondingly. The switching frequency variation for the different input and output voltages is shown in Figure 7. In this case the parameters of equation above are the following: Radd = 49.9 k $\Omega$ , Cadd = 1060 pF, Tdel1 = 240 ns, Tdel2 = 250 ns, Hyst = 0.5% of  $V<sub>O</sub>$ . The lower-switching frequency at higher input voltages helps to keep low switching losses during the input voltage range.



**Figure 7. Theoretical (Solid) and Measured (Points) Switching Frequency**

#### **output voltage**

The output voltage with a dc decoupling capacitor (C13) is defined below:

$$
V_{\mathbf{O}} = V_{\mathsf{ref}} \times \left(1 + \frac{R1}{R2}\right)
$$

where,  $R1 = R13$  and  $R2 = R16$  (see Figure 1)

#### **additional literature**

An Analytical Comparison of Alternative Control Techniques for Powering Next-Generation Microprocessors, SEM–1400 TI/Unitrode Power Supply Design Seminar, Topic 1.



**MECHANICAL DATA**

**DA (R-PDSO-G\*\*) PLASTIC SMALL-OUTLINE**



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-153



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